

<b>Notice of References Cited</b>	Application/Control No. 10/633,360	Applicant(s)/Patent Under Reexamination FLAUTNER, KRISZTIAN	
	Examiner Sean Weinman	Art Unit 2115	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,141,762	10-2000	Nicol et al.	713/300
X	B	US-5,627,412	05-1997	Beard, Paul	307/82
X	C	US-2002/0095610	07-2002	Nunomura, Yasuhiro	713/322
X	D	US-2003/0014457	01-2003	Desai et al.	708/520
X	E	US-2003/0135768	07-2003	Knee et al.	713/300
X	F	US-2002/0188877	12-2002	Buch, Deep K.	713/320
X	G	US-5,812,860	09-1998	Horden et al.	713/322
X	H	US-2002/0083356	06-2002	Dai, Xia	713/322
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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